

INFORMATION DISCLOSURE STATEMENT TRANSMITTAL

To Commissioner For Patents

Enclosed herewith is a Form PTO-1449, required copies of documents listed thereon, and a concise explanation of their relevance is described below or enclosed herewith per 37 CFR 1.97.

Application Number

Filing Date

CONCURRENTLY

First Named Inventor

Rene Monshouwer
et al

Group Art Unit

Examiner Name

Attorney Docket Number

NI 000771

U.S. PTO
09/040818

#4
180201
R. Talb

These documents may be relevant in that they have been:

- ☒ considered in drafting the specification of the above-referenced application;
- ☒ cited in the specification of the above-referenced application;
- ☐ previously submitted or cited in U.S. patent application(s) _____ which are relied on for an earlier effective filing date under 35 U.S.C. 120 (no copy required); or
- ☐ cited as an "X" or "Y" document in a foreign Patent Office search report on a foreign counter part application, a copy of which report is also enclosed;
☐ I hereby certify that these documents were first cited in any communication with a foreign Patent Office for a counterpart foreign application not more than three (3) months ago;
- ☐ Otherwise a concise explanation of the relevance of each document is append hereto.
☐ I hereby certify that not one of these documents was cited in any communication with a foreign Patent Office nor was any known to any individual designated in §1.56(c) more than three (3) months ago.

SIGNATURE OF APPLICANT, ATTORNEY, OR AGENT REQUIRED

Name (Print Type)

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Registration No. (Attorney/Agent)

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Signature

Michael E. Marion

Date

August 28, 2001

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| Form PTO-1449 U.S. DEPARTMENT OF COMMERCE (REV. 7-80) PATENT AND TRADEMARK OFFICE | | | | | | | | | | DOCKET NO. N1 000771 | | Serial No. | |
| INFORMATION DISCLOSURE CITATION (Use several sheets if necessary) | | | | | | | | | | Applicant Rene Monshouwer et al | | | |
| | | | | | | | | | | Filing Date Concurrently | | Group | |

| U.S. PATENT DOCUMENTS | | | | | | | | | | | | | |
|-----------------------|-----------------|---|---|---|---|---|---|---|----------|-----------------|-------|-----------|------------------------|
| Ex. Int. | Document Number | | | | | | | | Date | Name | Class | Sub-class | Filing Date If Approp. |
| | AA | 4 | 7 | 3 | 7 | 8 | 2 | 3 | 4/12/88 | Bouwer et al | 355 | 53 | 10/14/86 |
| | AB | 5 | 0 | 2 | 6 | 1 | 6 | 6 | 6/25/91 | Van der Werf | 356 | 401 | 10/1/84 |
| | AC | 5 | 1 | 9 | 1 | 2 | 0 | 0 | 3/2/93 | Van der Werf | 250 | 201 | 12/16/91 |
| | AD | 4 | 3 | 5 | 6 | 3 | 9 | 2 | 10/26/82 | Wittekoek et al | 250 | 201 | 6/11/80 |
| | AE | 4 | 8 | 6 | 1 | 1 | 6 | 2 | 8/29/89 | Ina et al | 356 | 401 | 11/15/88 |
| | AF | 5 | 4 | 1 | 4 | 5 | 1 | 4 | 5/9/95 | Smith et al | 356 | 363 | 6/1/93 |
| | AG | 4 | 7 | 7 | 8 | 2 | 7 | 5 | 10/18/88 | Van den Brink | 356 | 401 | 9/24/86 |
| | AH | 4 | 2 | 5 | 1 | 1 | 6 | 0 | 2/17/81 | Bouwhuis et al | 356 | 401 | 7/13/78 |
| | AI | 5 | 2 | 4 | 3 | 1 | 9 | 5 | 9/7/93 | Nishi | 250 | 548 | 12/29/92 |

| FOREIGN PATENT DOCUMENTS | | | | | | | | | | | | | | | | |
|--------------------------|----|-----------------|----|---|---|---|---|---|---|------|---------|--------|-----------|--------|---|--|
| | | Document Number | | | | | | | | Date | Country | Class | Sub-Class | Trans. | | |
| | | Yes | No | | | | | | | | | | | | | |
| | AJ | 0 | 4 | 9 | 8 | 4 | 9 | 9 | A | 1 | 8/12/92 | Europe | | | X | |
| | AK | 9 | 8 | 3 | 9 | 6 | 8 | 9 | A | 1 | 9/11/98 | World | | | X | |

| OTHER (Including Author, Title, Date, Pertinent Pages, Etc.) | |
|--|---|
| | AL "Submicrometer Lithographic Alignment and Overlay Strategies", by Saleem H. Zaidi et al, SPIE Vol. 1343, 1990, pages 245-255. |
| | AM "Overlay Accuracy Measurement Technique using the Latent Image on a Chemically Amplified Resist", by K. Yamashita et al., J. Appl. Phys. Vol. 35, 1996, pages 56-60. |
| | AN "Submicron 1:1 Optical Lighography", by David A. Markle, Semiconductor International May 1986. |
| Examiner _____ Date Considered _____ | |